



PATENT

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In the application of:
Charles J. Molnar

Case number: **1DTLB12803**

Application no.: **10/730631**

Group art: **3723**

Filed: **12-8-03**

Examiner: **Anthony Ojini**

For: **In situ finishing control**

Date: 4-26-04

Information Disclosure Statement

Mail Stop DD
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Sir:

In compliance with 37 CFR 1.56, 1.97, and 1.98, Applicants bring to the attention of the U. S. Patent and trademark Office information listed in the enclosed PTO-1449. A copy of the information is also enclosed.

Applicant, for convenience of PTO, lists pending and / or published applications for consideration:

Application Number	Filing date	Related publication / patent
09/538,409	3-29-00	6568989
09/939,957	8-27-01	
10/251,341	9-20-02	
10/260,458	9-30-02	
10/261,113	9-30-02	
10/730,631	12-8-03	

Very Respectfully Yours,

Charles J. Molnar

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Enclosed herewith:

For Application #: 10/730 631 Filed 12-8-03 +
having Private # 1DTLB12803

Information Disclosure Letter

PTO 1449 completed (4 pgs)

Copies of cited art

Return self-addressed Postcard:

Form PTO-1449 (modified by applicant)	Dock. #: IDTLB12803	Applic #: 10/730631
Information disclosure citation in an application	Filing Date: 12/8/03	Group art unit: 3723
Applicants: Charles J. Molnar/		

US Documents

Exam Initial	Document number	Date	Name	Class	Sub class	Filing date if approp.
	6568989	5-27-03	Molnar	451	5	
	6526547	2-25-03	Breiner et al.	716	4	
	6408227	6-18-02	Singhvi et al.	700	266	
	6298470	8-2-01	Breiner et al.	716	4	
	6293851	9-25-01	Molnar	451	41	
	6291349	9-18-01	Molnar	438	609	
	6283829	9-4-01	Molnar	451	8	
	6268641	7-31-04	Yano et al	257	620	
	6267644	7-31-01	Molnar	451	41	
	6263255	7-17-01	Tan et al.	700	121	
	6257953	7-10-01	Gittis et al.	451	5	
	6197604	3-6-01	Miller	438	14	
	6157916	12-5-00	Hoffman	705	8	
	6128540	10-3-00	Van Der Vegt et al.	700	36	
	6121143	9-19-00	Messner et al.	438	692	
	6056781	5-2-00	Wassick et al.	703	12	
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	5993298	11-30-99	Duescher	451	56	
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	5985045	11-16-99	Kobayashi	148	240	
	5972793	10-26-99	Tseng	438	692	
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	5954975	9-21-99	Cadien	216	38	

Foreign Patent Documents

Exam Initial	Document number	Date	Name	Class	Sub class	Filing date if approp.
	WO 99/64527	12-16-99	Sachan et al.	C09G	1/02	
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	WO 00/00567	1-6-00	Kaufman et al.	C09K	3/14	
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Other documents (including Author, Title, Date, Pertinent pages, etc.)

	6204181 withdrawn from issue, Molnar, filed 11-5-99, published March 20, 2001, serial number 09/438180
	BERMAN, MIKE et al., "Review of in Situ and in Line Detection for CMP Applic.", Semiconductor Fabtech, 8 th edition, pp. 267-274.
	BIBBY, THOMAS, "Endpoint Detection for CMP", Journal of Electronic Materials, Vol. 27, #10, 1998, pp. 1073-1081.

Examiner:	Date considered:
Examiner: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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	5954347	8-31-99	Wright	438	692	
	5934978	8-31-99	Burke	451	A36	
	5919082	7-6-99	Walker	451	41	
	5916855	6-29-99	Avanzino	51	307	
	5910041	6-8-99	Duescher	451	28	
	5906754	5-25-99	Appel	216	88	
	5885334	3-23-99	Suzuki	438	639	
	5885137	3-23-99	Ploessl	106	3	
	5876490	3-2-99	Ronay	106	3	
	5876266	3-1-99	Miller	451	56	
	5860847	1-19-99	Sakurai et al.	451	10	
	5858813	1-12-99	Scherber	438	693	
	5842909	12-1-98	Sandhu	451	7	
	5833519	11-10-98	Moore	451	56	
	5830280	11-3-98	Sato	134	2	
	5799286	8-25-98	Morgan et al.	705	30	
	5783489	7-21-98	Kaufman	438	692	
	5774633	6-30-98	Baba et al.	395	23	
	5762537	6-9-98	Sandhu	451	7	
	5759917	6-2-98	Grover et al.	438	690	
	5749769	5-12-98	Church	451	5	
	5743784	4-28-98	Birang	451	21	
	5740033	4-14-98	Wassick et al.	364	149	
	5738562	4-14-98	Doan	451	5	
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	5733819	3-31-98	Kodama	438	692	
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	5728308	3-17-98	Muroyama	216	88	
	5722879	3-3-98	Cronin	451	281	
	5695660	12-9-97	Litvak	216	85	
	5695384	12-9-97	Beratan	451	28	

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Other documents (including Author, Title, Date, Pertinent pages, etc.)

	"Understanding and Using Cost of Ownership", Wright Williams & Kelly, Dublin, CA, rev 0595-1
	"Intermetal Dielectric Cost-of-Ownership", Case, C.B. and Case, C. J., <u>Semiconductor International</u> , June 1995, pp 83-88
	"Using COO to select Nitride PECVD clean cycle", Anderson, Bob, et al., <u>Semiconductor International</u> , Oct. 1993, pp 86-88
	"The application of cost of ownership simulation to wafer sort and final test", Jimez, D. W. et al., SEMI's Manufacturing test Conference, July, 1993
	"Reducing Tungsten Deposition equipment cost of ownership through in situ contamination prevention and reduction", Burghard, R. W., et al., <u>Microcontamination</u> , Oct. 1992, pp 23-25
	"Reducing ion-implant equipment cost of ownship through in situ contamination prevention and control", Burghard, R. W., et al., <u>Microcontamination</u> , Sept. 1992, pp 27-30
	"Reducing tungsten-etch equipment cost of ownership through in situcontamination prevention and reduction", Burghard, R. W., et al., <u>Microcontamination</u> , June 1992, pp 33-36
	"Reducing process equipment cost of ownership through in situ contamination prevention and reduction", Burghard, R. W., et al., <u>Microcontamination</u> , May. 1992, pp 21-24
	"Cost of ownership for inspection equipment", Dance D. and Bryson, P., Sematech, Austin, Texas, date unknown

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	5597442	1-28-97	Chen	156	626.1	
	5595526	1-21-97	Yau	451	8	
	5537325	7-16-96	Iwakiri et al.	364	468.28	
	5521814	5-28-96	Teran et al.	364	402	
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	5413941	5-9-95	Koos	437	8	
	5352277	10-24-94	Sasaki	106	6	
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